



SINGLE M-LVDS RECEIVERS

FEATURES

- Low-Voltage Differential 30-Ω to 55-Ω Line Receivers for Signaling Rates⁽¹⁾ up to 250Mbps; Clock Frequencies up to 125MHz
- SN65MLVD2 Type-1 Receiver Incorporates 25 mV of Input Threshold Hysteresis
- SN65MLVD3 Type-2 Receiver Provides 100 mV Offset Threshold to Detect Open-Circuit and Idle-Bus Conditions
- Wide Receiver Input Common-Mode Voltage Range, –1 V to 3.4 V, Allows 2 V of Ground Noise
- Improved V_{IT} (35 mV)
- Meets or Exceeds the M-LVDS Standard TIA/EIA-899 for Multipoint Topology
- High Input Impedance with Low Supply Voltage
- Bus-Pin HBM ESD Protection Exceeds 9 kV
- Packaged in 8-Pin SON (DRB) 70% Smaller Than 8-Pin SOIC
- (1) The signaling rate of a line is the number of voltage transitions that are made per second, expressed in the units bps (bits per second).

DESCRIPTION

The SN65MLVD2 and SN65MLVD3 are single-channel M-LVDS receivers. These devices are designed in full compliance with the TIA/EIA-899 (M-LVDS) standard, which are optimized to operate at signaling rates up to 250 Mbps. Each receiver channel is controlled by a receive enable (\overline{RE}). When \overline{RE} = low, the corresponding channel is disabled.

The M-LVDS standard defines two types of receivers, designated as Type-1 and Type-2. Type-1 receivers (SN65MLVD2) have thresholds centered about zero with 25 mV of hysteresis to prevent output oscillations with loss of input; Type-2 receivers (SN65MLVD3) implement a failsafe by using an offset threshold. Receiver outputs are slew rate controlled to reduce EMI and crosstalk effects associated with large current surges.

The devices are characterized for operation from -40°C to 85°C.

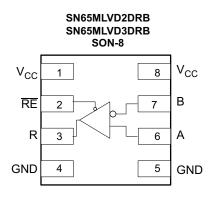


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

APPLICATIONS

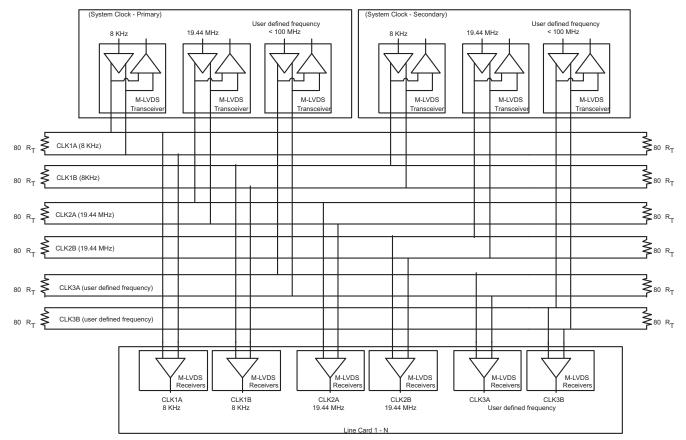
- Parallel Multipoint Data and Clock Transmission via Backplanes and Cables
- Cellular Base Stations
- Central Office Switches
- Network Switches and Routers

PACKAGE AND PIN-OUT





TYPICAL APPLICATION



AdvancedTCA Backplane - Synchronized System Clock



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ORDERING INFORMATION⁽¹⁾

PART NUMBER	FUNCTION	PART MARKING	PACKAGE / CARRIER
SN65MLVD2DRBT	M-LVDS Type 1 Receiver	MF2	8-Pin SON / Small Tape and Reel
SN65MLVD2DRBR	M-LVDS Type 1 Receiver	MF2	8-Pin SON / Tape and Reel
SN65MLVD3DRBT	M-LVDS Type 2 Receiver	MF3	8-Pin SON / Small Tape and Reel
SN65MLVD3DRBR	M-LVDS Type 2 Receiver	MF3	8-Pin SON / Tape and Reel

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) ⁽¹⁾

				VALUE	UNIT
V _{CC}	Supply voltage range ⁽²⁾			–0.5 to 4	V
	lonut voltage ronge	RE		-0.5 to 4	V
	Input voltage range	A or B	-1.8 to 4	V	
	Output voltage range	R		-0.3 to 4	V
		Human-body model ⁽³⁾	All other pins	±7	kV
	Electrostatio discharge		А, В	±9	ĸv
	Electrostatic discharge	Machine model ⁽⁴⁾	All pins	±200	V
		Field-induced-charged-device model ⁽⁵⁾	All pins	±2	kV
	Continuous power dissipa	See Dissipation Rating Table			

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

(3) Tested in accordance with JEDEC Standard 22, Test Method A114-A. Bus pin stressed with respect to a common connection of GND and V_{CC}.

(4) Tested in accordance with JEDEC Standard 22 Test Method A115-A.

(5) Tested in accordance with EIA-JEDEC JESD22-C101C.

PACKAGE DISSIPATION RATINGS⁽¹⁾

PACKAGE			DERATING FACTOR ⁽²⁾ ABOVE T _A = 25°C	T _A = 85°C POWER RATING
	Low-K	280 mW	2.80 mW/°C	112 mW
8-SON DRB	High-K	662 mW	6.62 mW/°C	264 mW

(1) The thermal dissipations are in the consideration of soldering down the powerPAD without via on each type of boards.

(2) This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

THERMAL CHARACTERISTICS

PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
θ_{JB}	Junction-to-board thermal resistance			89		° C/W
θ_{JC}	Junction-to-case thermal resistance			98		° C/W
P_D	Device power dissipation	$\overline{\text{RE}}$ at 0 V, C _L = 15 pF, V _{ID} = 400 mV, 125 MHz			90	mW

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	3	3.3	3.6	V
V _{IH}	High-level input voltage	2		V_{CC}	V
V _{IL}	Low-level input voltage	GND		0.8	V
$V_{A} \text{ or } V_{B}$	Voltage at any bus terminal	-1.4		3.8	V
V _{ID}	Magnitude of differential input voltage	0.035		V_{CC}	V
V _{IC}	Differential common-mode input voltage	-1		3.4	V
RL	Differential load resistance	30	50		Ω
1/t _{UI}	Signaling rate			250	Mbps
T _A	Operating free-air temperature	-40		85	°C

DEVICE ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		TYP ⁽¹⁾	МАХ	UNIT
IC	C Supply current	\overline{RE} at 0 V, C _L = 15 pF, V _{ID} = 400 mV, 125 MHz			25	mA

(1) All typical values are at 25°C and with a 3.3-V supply voltage.

RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+}	Positive-going differential input voltage T					35	
	threshold	Type 2				135	mV
V _{IT-}	Negative-going differential input voltage	Type 1	Cas Figure 4 Table 4 and Table 2	-35			
	threshold	Type 2	See Figure 1, Table 1 and Table 2	65			mV
V _{HYS}	Differential input voltage hysteresis	Type 1			25		
	(V _{IT+} - V _{IT-})	Type 2			0		mV
V _{OH}	High-level output voltage		I _{OH} = -8 mA	2.4			V
V _{OL}	Low-level output voltage		I _{OL} = 8 mA			0.4	V
I _{IH}	High-level input current		$V_{IH} = 2 V \text{ to } V_{CC}$	-10			μA
IIL	Low-level input current		$V_{IL} = GND \text{ to } 0.8 \text{ V}$	-10			μA
I _{OZ}	High-impedance output current		$V_{O} = 0 V \text{ or } V_{CC}$	-10		15	μA
I_A or I_B	Receiver input current		One input (V _A or V _B) = -1.4 V or 3.8 V, Other input = 1.2 V	-20		20	μA
I _{AB}	Receiver differential input current (I _A - I _B)		$V_{A} = V_{B} = -1.4$ V or 3.8 V	-4		4	μA
$I_{A(OFF)}$ or $I_{B(OFF)}$	Receiver input current		One input (V _A or V _B) = -1.4 V or 3.8 V, Other input = 1.2 V, V _{CC} = GND or 1.5 V	-20		20	μΑ
I _{AB(OFF)}	Receiver power-off differential input current (I_A– $\rm I_B)$		$V_{\rm A}$ = $V_{\rm B}$ = -1.4 V or 3.8 V, $V_{\rm CC}$ = GND or 1.5 V	-4		4	μΑ
$C_A \text{ or } C_B$	B Input capacitance		$V_{\rm I} = 0.4 sin(30 E6 \pi t) + 0.5 V,^{(2)}$ Other input at 1.2 V		3		pF
C _{AB}	Differential input capacitance	V _{AB} = 0.4sin(30E6πt) + 0.5 V ⁽²⁾			2.5	pF	
C _{A/B}	Input capacitance balance, (C _A /C _B)			0.99		1.01	

(1) All typical values are at $25^{\circ}C$ and with a 3.3-V supply voltage.

(2) HP4194A impedance analyzer (or equivalent)

RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		2		6	ns	
t _{PHL}	Propagation delay time, high-to-low-level output			2		6	ns
t _r	Output signal rise time			1		2.3	
t _f	Output signal fall time		$C_L = 15 \text{ pF}$, See Figure 2	1		2.3	ns
+		Type 1			90	210	20
t _{sk(p)}	Pulse skew (t _{PHL} - t _{PLH})	Type 2			45	250	ps
t _{sk(pp)}	Part-to-part skew	-			1	ns	
t _{jit(per)}	Period jitter, rms (1 standard deviation) ⁽²⁾	125 MHz clock input			10	ps	
t _{jit(c-c)}	Cycle-to-cycle jitter, rms ⁽³⁾		125 MHz clock input ⁽⁴⁾			8	ps
+	Deterministic jitter ⁽²⁾	Type 1	250 Mbps 2 ¹⁵ -1 PRBS input ⁽⁵⁾			500	ps
t _{jit(det)}		Type 2				450	ps
	Type 1		250 Mhas 215 4 DDDC input(5)			8	ps
t _{jit(ran)}	Random jitter ⁽²⁾	Type 2	250 Mbps 2 ¹⁵ -1 PRBS input ⁽⁵⁾			8	ps
t _{PZH}	Enable time, high-impedance-to-high-level output		C _L = 15 pF, See Figure 3			15	ns
t _{PZL}	Enable time, high-impedance-to-low-level output		C _L = 15 pF, See Figure 3			15	ns
t _{PHZ} Disable time, high-level-to-high-impedance output			C _L = 15 pF, See Figure 3			10	ns
t _{PLZ}	Disable time, low-level-to-high-impedance output		C _L = 15 pF, See Figure 3			10	ns

All typical values are at 25°C and with a 3.3-V supply voltage.
 Jitter measured by triggering off of the input source to track out the associated input jitter.
 Stimulus jitter has been subtracted from the numbers.

Measured over 75K samples Measured over BER = 10^{-6} . (4) (5)

TERMINAL FUNCTIONS

TE	TERMINAL I/O		DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
A	6	I	M-LVDS Non-inverting input
В	7	I	M-LVDS Inverting input
R	3	0	Data output from receivers
RE	2	I	Receiver enable, active low, enables all receivers
GND	4, 5		Circuit ground
V _{CC}	1, 8		Supply voltage

DEVICE FUNCTION TABLES

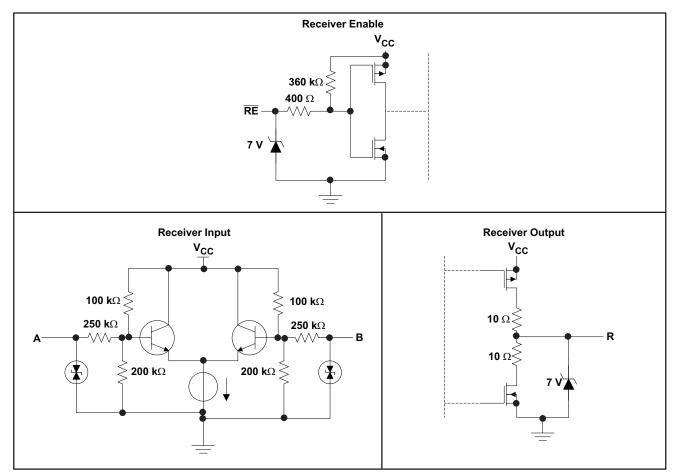
TYPE-1 RECEIVER (SN65MLVD2)			TYPE-2 RECEIVER (SN65ML	VD3)
INPUTS ⁽¹⁾		OUTPUT ⁽¹⁾	INPUTS ⁽¹⁾	OUTPUT ⁽¹⁾
$V_{ID} = V_A - V_B$	RE	R	$V_{ID} = V_A - V_B$ RE	R
$V_{ID} \ge 35 \text{ mV}$	L	Н	$V_{ID} \ge 135 \text{ mV}$ L	Н
$-35 \text{ mV} \le \text{V}_{\text{ID}} \le 35 \text{ mV}$	L	?	$65 \text{ mV} \le \text{V}_{\text{ID}} \le 135 \text{ mV}$ L	?
V _{ID} ≤– 35 mV	L	L	$V_{ID} \le 65 \text{ mV}$ L	L
Х	Н	Z	ХН	Z
Х	Open	Z	X Oper	Z
Open Circuit	L	?	Open Circuit L	L

(1) H=high level, L=low level, Z=high impedance, X=Don't care, ?=indeterminate

SN65MLVD2 SN65MLVD3 SLLS767-NOVEMBER 2006



EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS



PARAMETER MEASUREMENT INFORMATION

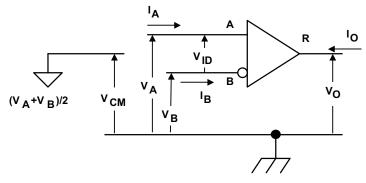


Figure 1. Receiver Voltage and Current Definitions

APPLIED VOLTAGES		RESULTING DIFFERENTIAL INPUT VOLTAGE	RESULTING COMMON-MODE INPUT VOLTAGE	RECEIVER OUTPUT ⁽¹⁾
VIA	VIB	V _{ID}	V _{IC}	
2.400	0.000	2.400	1.200	Н
0.000	2.400	- 2.400	1.200	L
3.400	3.365	0.035	3.3825	Н
3.365	3.400	- 0.035	3.3825	L
-0.965	-1	0.035	-0.9825	Н
-1	-0.965	- 0.035	-0.9825	L

Table 1. Type-1 Receiver Input Threshold Test Voltages

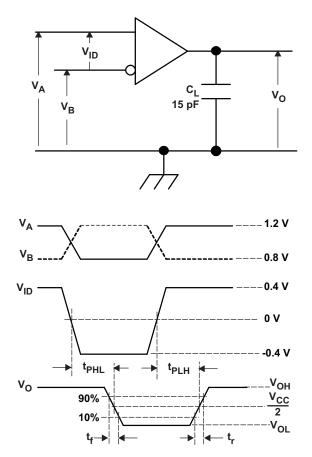
(1) H= high level, L = low level, output state assumes receiver is enabled ($\overline{RE} = L$)

Table 2. Type-2 Receiver Input Threshold Test Voltages

APPLIED VOLTAGES		RESULTING DIFFERENTIAL INPUT VOLTAGE	RESULTING COMMON-MODE INPUT VOLTAGE	RECEIVER OUTPUT ⁽¹⁾
VIA	V _{IB}	V _{ID}	V _{IC}	
2.400	0.000	2.400	1.200	Н
0.000	2.400	- 2.400	1.200	L
3.400	3.265	0.135	3.3325	Н
3.4000	3.335	0.065	3.3675	L
-0.865	-1	0.135	-0.9325	Н
-0.935	-1	0.065	-0.9675	L

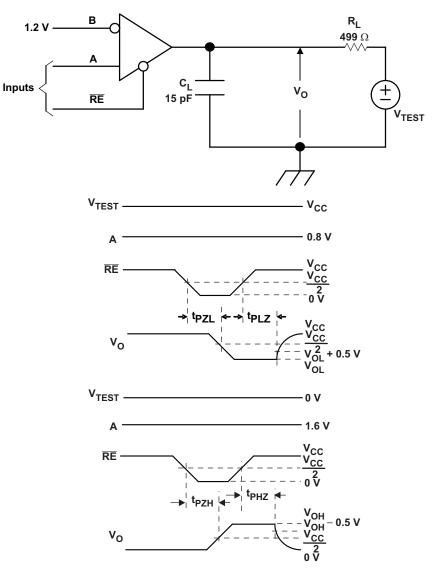
(1) H= high level, L = low level, output state assumes receiver is enabled ($\overline{RE} = L$)





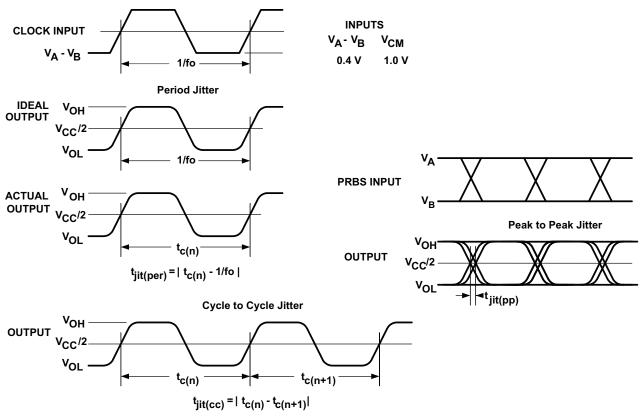
- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, Frequency = 1 MHz, duty cycle = 50 ± 5%. C_L is a combination of a 20%-tolerance, low-loss ceramic, surface-mount capacitor and fixture capacitance within 2 cm of the D.U.T.
- B. The measurement is made on test equipment with a -3dB bandwidth of at least 1 GHz.

Figure 2. Receiver Timing Test Circuit and Waveforms



- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, frequency = 1 MHz, duty cycle = $50 \pm 5\%$.
- B. R_L is 1% tolerance, metal film, surface mount, and located within 2 cm of the D.U.T
- C. C_L is the instrumentation and fixture capacitance within 2 cm of the D.U.T. and ±20%. The measurement is made on test equipment with a –3dB bandwidth of at least 1GHz.

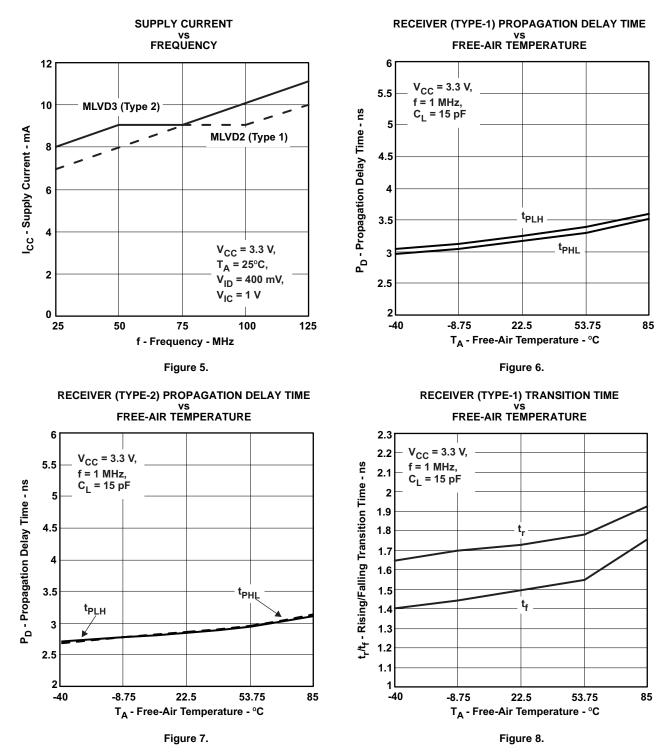
Figure 3. Receiver Enable/Disable Time Test Circuit and Waveforms



- A. All input pulses are supplied by the Agilent 81250 Parallel BERT Stimulus System with plug-in E4832A.
- B. The cycle-to-cycle jitter measurement is made on a TEK TDS6604 running TDSJIT3 application software
- C. Period jitter is measured using a 125-MHz 50 \pm 1% duty cycle clock input.
- D. Deterministic jitter and random jitter are measured using a 250-Mbps 2¹⁵⁻¹ PRBS input

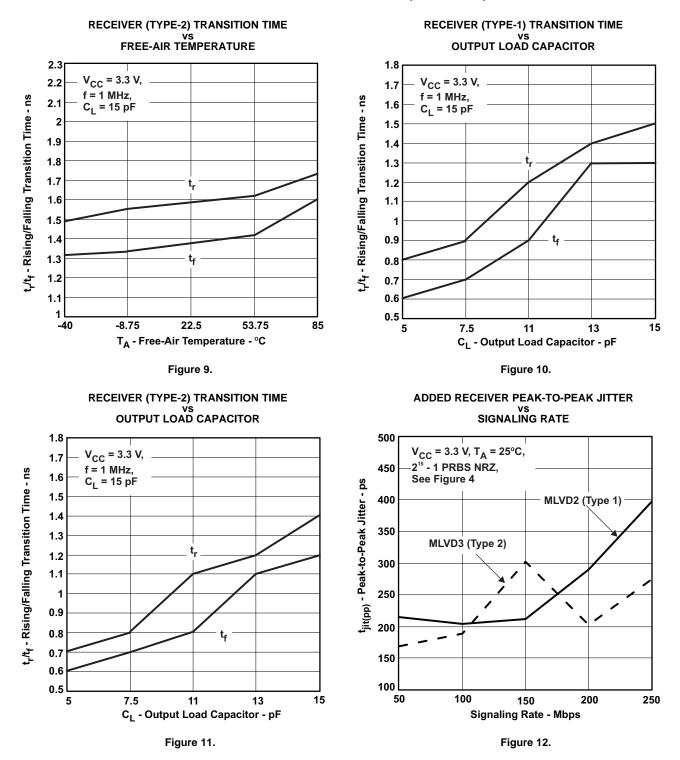
Figure 4. Receiver Jitter Measurement Waveforms

TYPICAL CHARACTERISTICS

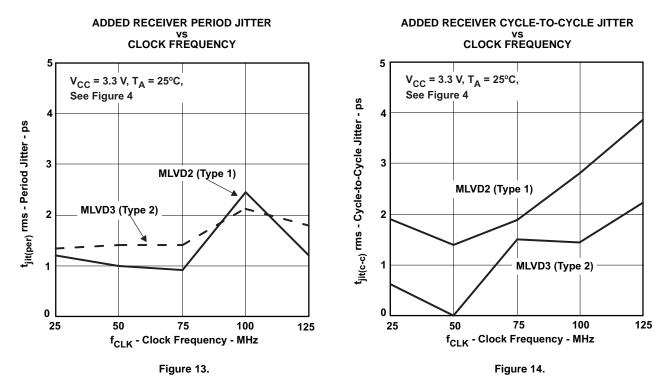




TYPICAL CHARACTERISTICS (continued)









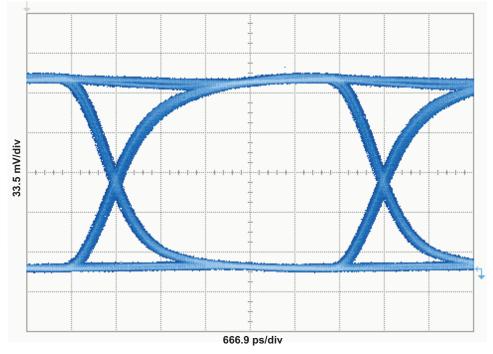


Figure 15. SN65MLVD2 Output (V_{CC} = 3.3 V, C_L = 15 pF) 250 Mbps 2^{15} -1 PRBS



TYPICAL CHARACTERISTICS (continued)

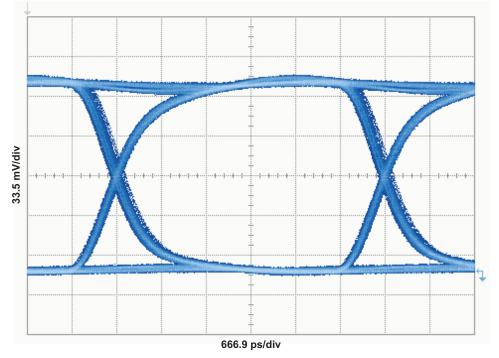


Figure 16. SN65MLVD3 Output (V_{CC} = 3.3 V, C_L = 15 pF) 250 Mbps 2^{15} –1 PRBS



17-May-2014

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
SN65MLVD2DRBR	ACTIVE	SON	DRB	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MF2	Samples
SN65MLVD2DRBRG4	ACTIVE	SON	DRB	8		TBD	Call TI	Call TI	-40 to 85		Samples
SN65MLVD2DRBT	ACTIVE	SON	DRB	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MF2	Samples
SN65MLVD2DRBTG4	ACTIVE	SON	DRB	8		TBD	Call TI	Call TI	-40 to 85		Samples
SN65MLVD3DRBR	ACTIVE	SON	DRB	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MF3	Samples
SN65MLVD3DRBRG4	ACTIVE	SON	DRB	8		TBD	Call TI	Call TI	-40 to 85		Samples
SN65MLVD3DRBT	ACTIVE	SON	DRB	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MF3	Samples
SN65MLVD3DRBTG4	ACTIVE	SON	DRB	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	MF3	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



www.ti.com

17-May-2014

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

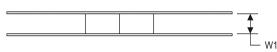
www.ti.com

TAPE AND REEL INFORMATION

REEL DIMENSIONS

Texas Instruments





TAPE AND REEL INFORMATION

TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65MLVD2DRBR	SON	DRB	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
SN65MLVD2DRBT	SON	DRB	8	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
SN65MLVD3DRBR	SON	DRB	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
SN65MLVD3DRBT	SON	DRB	8	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

TEXAS INSTRUMENTS

www.ti.com

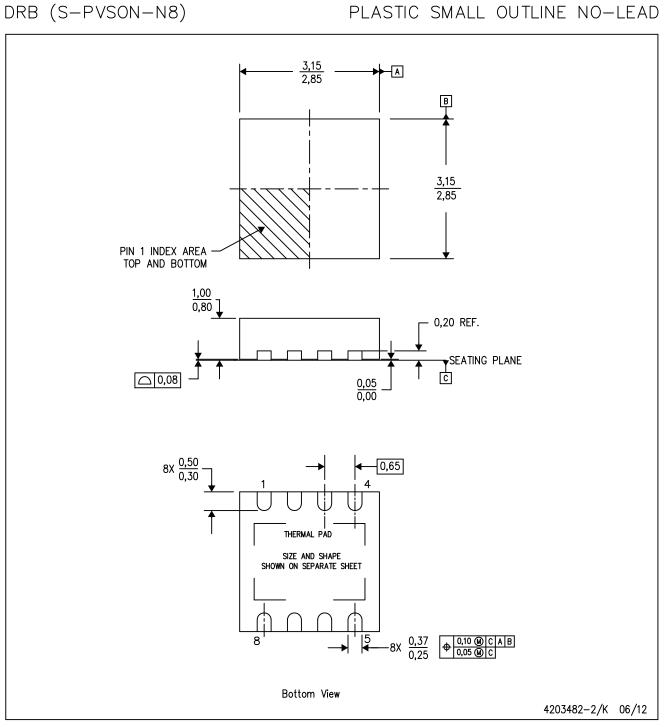
PACKAGE MATERIALS INFORMATION

14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65MLVD2DRBR	SON	DRB	8	3000	367.0	367.0	35.0
SN65MLVD2DRBT	SON	DRB	8	250	210.0	185.0	35.0
SN65MLVD3DRBR	SON	DRB	8	3000	367.0	367.0	35.0
SN65MLVD3DRBT	SON	DRB	8	250	210.0	185.0	35.0



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Small Outline No-Lead (SON) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.



THERMAL PAD MECHANICAL DATA

DRB (S-PVSON-N8)

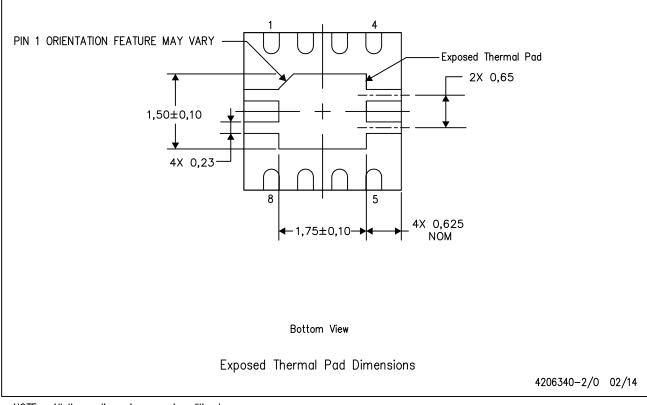
PLASTIC SMALL OUTLINE NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

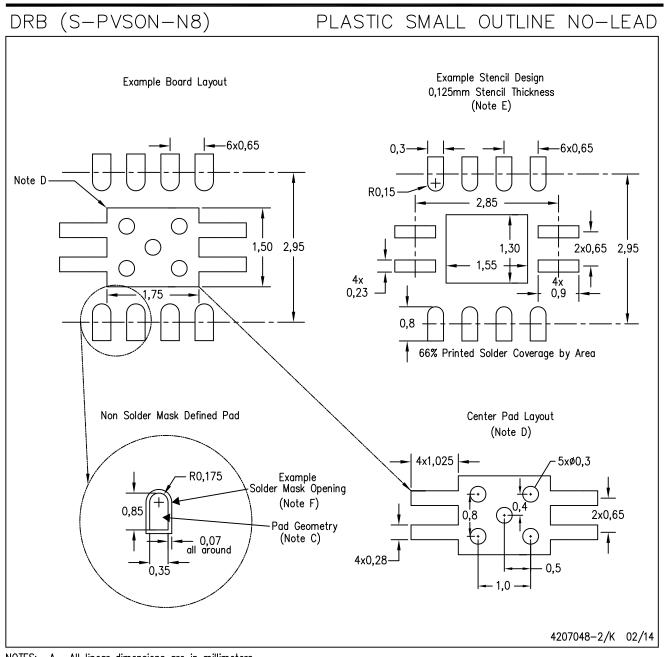
For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.









NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, QFN Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for solder mask tolerances.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconne	ectivity	

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2014, Texas Instruments Incorporated